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| Notice of References Cited | Application/Control No. 10/600,014 | Applicant(s)/Patent Under Reexamination CHATTERJEE ET AL. | |
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U.S. PATENT DOCUMENTS

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| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|-------------------------------------------------------------------------------------------------------------------------------------------------------|
| | U | Electrical Schematics Page, April 25, 2002, http://www.jlab.org/accel/inj_group/elec1.htm |
| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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